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# A Template and Catalyst-Free Metal-Etching-Oxidation Method to Synthesize Aligned Oxide Nanowire Arrays: NiO as an Example

**an Example** Zhi Peng Wei,<sup>†</sup> Miryam Arredondo,<sup>‡</sup> Hai Yang Peng,<sup>†</sup> Zhou Zhang,<sup>†</sup> Dong Lai Guo,<sup>†</sup> Guo Zhong Xing,<sup>†</sup> Yong Feng Li,<sup>†</sup> Lai Mun Wong,<sup>§</sup> Shi Jie Wang,<sup>§</sup> Nagarajan Valanoor,<sup>‡</sup> and Tom Wu<sup>\*,†</sup>

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eterministic synthesis of one-10 dimensional (1D) crystalline 11 nanowires (NWs) with controlled 12 morphologies and properties is currently a 13 major objective in nanosciences and nano-14 technologies.<sup>1</sup> Various synthesis routes 15 have been developed, and their applica-16 tions to NW synthesis have been intensively 17 pursued. Compared with the solution-18 19 based methods, vapor transport growth 20 has the advantage of being more environmentally friendly and often can give NWs 21 with high aspect ratios, which is critical for 22 many key applications. Vapor-liquid-solid 23 (VLS) growth is one of the most popular 24 synthesis methods, where liquid-state cata-25 lyst nanoparticles absorb the precursor va-26 27 por and NW growth starts when supersaturation is reached in the nanoparticles.<sup>2-5</sup> 28 Recently, a variant that uses solid-state cata-29 30 lysts at lower temperatures, termed as the "vapor-solid-solid" (VSS) growth, has also 31 been devised to grow NWs.<sup>6</sup> In another dis-32 33 tinct approach without the use of catalyst, NW synthesis has been accomplished 34 through the vapor-solid (VS) route.<sup>7,8</sup> 35 Among all the techniques to produce NWs, 36 37 the hot plate method is probably the most convenient and cost-effective, where heat-38 ing metal foils in either atmosphere or con-39 trolled environment was found to give 1D 40 nanomaterials.9 Complementary to the 41 above vapor-based routes, template-42 assisted methods have been employed to 43 44 produce NWs with uniform size; for example, liquid or gas phase precursors were 45 filled into the pores of anodic aluminum ox-46

**ABSTRACT** Although NiO is one of the canonical functional binary oxides, there has been no report so far on the effective fabrication of aligned single crystalline NiO nanowire arrays. Here we report a novel vapor-based metal-etching-oxidation method to synthesize high-quality NiO nanowire arrays with good vertical alignment and morphology control. In this method, Ni foils are used as both the substrates and the nickel source; NiCl<sub>2</sub> powder serves as the additional Ni source and provides Cl<sub>2</sub> to initiate mild etching. No template is deliberately employed; instead a nanograined NiO scale formed on the NiO foil guides the vapor infiltration and assists the self-assembled growth of NiO nanowires *via* a novel process comprising simultaneous Cl<sub>2</sub> etching and gentle oxidation. Furthermore, using CoO nanowires and Co-doped NiO as examples, we show that this general method can be employed to produce nanowires of other oxides as well as the doped counterparts.

**KEYWORDS:** nickel oxide · nanowire · metal-etching-oxidation method · catalyst · self-assembly

ide (AAO) membranes to render either NWs 47 or nanotubes.<sup>10</sup> 48 However, it is well recognized that for 49 some materials the currently available syn-50 thesis methods are not very effective to en-51 able the anisotropic growth of 1D NWs. 52 This is in particular true for materials with 53 cubic crystal symmetries which lack the 54 structural anisotropy critically needed for 55 the growth of single crystalline NWs. Syn-56 thesis of these oxide NWs requires develop-57 ing novel routes beyond the conventional 58 ones. Nickel oxide (NiO) is one of such no-59 table materials. NiO is an important mem-60 ber in the family of binary oxides with a cu-61 bic rock salt structure and a lattice \*Address correspondence to 62 tomwu@ntu.edu.sg. parameter of 0.4195 nm. Several decades 63 ago, NiO played a very critical role in the de-64 Received for review March 16, 2010 velopment of the modern solid state physand accepted July 01, 2010. 65 ics by revealing the limitation of the free 66 electron model and the critical role of 67 10.1021/nn1005396 strong electron correlation.<sup>11</sup> Today, NiO is 68 an important p-type semiconductor © XXXX American Chemical Society 69 VOL. XXX • NO. XX • 000-000 • XXXX ACS A.

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Figure 1. (a) Schematic of the experimental setup. This figure is not drawn to scale. Photographs of (b) polished Ni foil, (c) Ni foil after NiO NW growth, and (d) NiO NW arrays after being transferred from the Ni foil to a flexible plastic substrate. (e) A typical SEM image of the NiO NW arrays. (f) SEM image of an individual NiO NW. The scale bar is 200 nm. (g) XRD spectrum of the NiO NW arrays. The NiO powder diffraction data (JCPDS Card No. 78-0423) is also shown at the bottom.

material<sup>12</sup> and has been extensively investigated because of its myriad applications in catalysts, <sup>13,14</sup> gas sensors,<sup>15</sup> battery materials,<sup>16</sup> electrochromic coatings,<sup>17</sup> and so on. It is also a canonical antiferromagnetic material with a Neel temperature of 523 K,18 and often used in magnetic multilaver devices.<sup>19,20</sup> Most recently, NiO showed excellent resistive switching behaviors and may find potential uses in nonvolatile memories.<sup>21,22</sup> Up to now, a variety of methods have been attempted to achieve nanostructured NiO, but all of them suffer from drawbacks. For example, solution-based chemical routes<sup>23</sup> and sol-gel methods<sup>24</sup> were shown to produce NiO NWs in large quantity, but the NWs have no alignment. Electrochemical deposition into anodic alumina membranes<sup>25,26</sup> and oxidation of NiS precursor in molten salt<sup>27</sup> were also employed to prepare NiO NWs. However, these two methods lead to only polycrystalline NWs. To the best of our knowledge, template-free synthesis of aligned single-crystal NiO NW arrays has not been reported.

In this study, we discovered a novel template- and catalyst-free method to synthesize high quality NiO NW arrays. This facile method involves controlled anisotropic etching of a nickel (Ni) foil through a NiO layer with low-pressure  $Cl_2$  vapor, which is accompanied by continuous oxidation. It is the first time, to our knowledge, that single-crystal NiO NW arrays were synthesized with a template-free method. Furthermore, we show that this method is a general approach to produce metal oxide NW arrays and can be used to dope the NWs by adjusting the vapor source.

### **RESULTS AND DISCUSSION**

The synthesis of the NiO NW arrays was carried out in a home-built vapor transport system comprising a horizontal tube furnace (Lindberg/Blue mini-mite) and a gas delivery and pumping system as described previously.<sup>28–30</sup> The schematic of the experimental

setup is shown in Figure 1a. Ni foils were cut into small 107 pieces, cleaned, mechanically polished, and electro-108 chemically polished. Finally, the Ni foils were annealed 109 to decrease the internal stress and to further improve 110 the crystalline quality (see Supporting Information Fig-111 ure S1). These presynthesis treatments are critical to 112 achieve (100) textured Ni foils with very flat surfaces. 113 The treated Ni foils (Figure 1b) were then put in the cen- 114 ter of the furnace between the small tubes containing 115 the NiCl<sub>2</sub> powder. We need to point out here that the Ni 116 foils serve as both the substrate and the nickel source. 117 Nickel chloride (NiCl<sub>2</sub>) powder was put into two small 118 one-end-open quartz tubes. After the growth process, 119 a layer of green products was grown on the surface of 120 the Ni foils. Figure 1c shows the optical image of the Ni 121 foil after growth. The green color indicates the pres-122 ence of NiO on the Ni foil. We found that NiO NWs are 123 not directly grown on the Ni foil, but imbedded under a 124 NiO film (the growth mechanism will be discussed in 125 details later on). Thus to reveal the NiO NW arrays, we 126 need to bond a supporting substrate to the sample us-127 ing either silver paste or double-sided tape, then the 128 NiO NWs can be conveniently transferred to the sub-129 strate by lift-off. Since the growth and transfer pro-130 cesses are separated, a supplementary advantage of 131 this method is that there is no limitation on selecting 132 the final supporting substrate. Figure 1d shows the op-133 tical image of a sample of NiO NW arrays being trans-134 ferred to a flexible plastic substrate. Figure 1e shows a 135 typical SEM image of the NiO NW arrays. The NiO NWs 136 are several micrometers in length and about one hun-137 dred nanometers in diameter. They are quite uniform 138 and appear well aligned. Figure 1f is the SEM image of 139 an individual NiO NW showing a smooth surface. The 140 chemical composition of the NWs was characterized by 141 XRD, and as shown in Figure 1g, only NiO related peaks 142 were detected. The relative intensity of the peaks dif-143 fers from the powder diffraction data (JCPDS Card No. 144

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145 78-0423), and the dominant (200) peak indicates a preferred (200) orientation. The absence of NiCl<sub>2</sub> or Ni re-146 lated peaks excludes the existence of any impurity 147 phase above the detection level. 148

149 The crystalline structure of the NiO NWs was further characterized by TEM. Figure 2a shows a low-resolution F2 150 TEM image of a NiO NW. The diameter of this particu-151 lar NW is about 130 nm. The selected area electron dif-152 fraction (SAED) pattern in Figure 2b can be indexed as 153 154 the cubic structure with no detectable secondary phase. The HRTEM image (Figure 2c) was recorded along the 155 [011] zone axis and it shows clear lattice fringes. The dis-156 tance between the lattice planes along the NW growth 157 direction is 0.208 nm, which is consistent with the lat-158 tice constant of the NiO unit cell. Both the SAED pattern 159 and the HRTEM image suggest that the NW is single 160 crystalline and the growth direction is along [200]. 161 Among a dozen NiO NWs we examined using HRTEM, 162 we also observed a few growing along [220] (Support-163 ing Information, Figure S2). Nevertheless, we found that 164 the majority of the NiO NWs are along the [200] direc-165 166 tion, which is in agreement with the XRD data.

We now discuss the tentative formation mecha-167 nism of the NWs which grow underneath the NiO over-168 layer. The schematic in Figure 3a-d illustrates the growth process of the NiO NW arrays. At the growth 170 171 temperature, three major reactions are involved:<sup>31</sup>

$$Ni(s) + 1 / 2O_2(g) \rightarrow NiO(s)$$
(1)

 $NiCl_2(g) + 1 / 2O_2(g) \rightarrow NiO(s) + Cl_2(g)$ (2)

$$Ni(s) + Cl_2(g) \rightarrow NiCl_2(g)$$
(3)

The high temperature oxidation of Ni and the forma-172 tion of NiO scale have been studied for many years.<sup>32</sup> 173 174 The oxidation reaction in eq 1 accelerates as the furnace temperature increases, which is accompanied by a 175 weight gain of the Ni foil (Supporting Information, Fig-176 ure S3). The formation of NiO is also confirmed by the 177 XRD data shown in Figure S4; the NiO [200] peak at 178 179 43.3° starts to appear and becomes stronger as the temperature increases. When the furnace temperature 180 reaches 600 °C, NiCl<sub>2</sub> powder starts to evaporate into 181 the gas form, which is evidenced by the rapid weight 182 loss of the NiCl<sub>2</sub> powder above this temperature (Fig-183 ure S3). The reaction 2 suggests that NiCl<sub>2</sub> vapor reacts 184 with  $O_2$  in the mixture gas to produce  $Cl_2$  gas. The exist-185 ence of Cl<sub>2</sub> gas can significantly affect the kinetics of 186 the oxidation process.<sup>31</sup> It is important to note that 187 there are many closely spaced microchannels across 188 the columnar NiO scale, and the gaseous species can 189 penetrate the scale along the fine grain boundaries.<sup>32</sup> 190 191 Subsequently, according to reaction 3, the Cl<sub>2</sub> gas diffuses through the NiO layer and etches the Ni substrate 192 underneath it. This process helps to gently sculpt the 193 continuous Ni foil into wire-like morphology as illus-194 trated in Figure 3c. According to the reaction 3, during 195



Figure 2. (a) Low resolution TEM image of a NiO NW. (b) SAED pattern and (c) HRTEM image taken on the same NW. The interplane distance of 0.208 nm is consistent with the lattice constant of NiO.

etching, additional NiCl<sub>2</sub> is produced in the gas form, which is fed back to reaction 2. Hence, NiCl<sub>2</sub> and Cl<sub>2</sub> are conserved, and the overall result is the oxidation of Ni. However, this balance is not strictly maintained in the experiments; NiCl<sub>2</sub> and Cl<sub>2</sub> in the gas form continuously escape from the samples and flow away with the carrying gas, which eventually terminates the reactions.

We should note that although no template is deliberately employed in the synthesis, the nanograined NiO scale serves as a mask guiding the infiltration of Cl<sub>2</sub> and O<sub>2</sub> gases. As illustrated in the schematics in Figure 3, concurrent to the etching process is the oxidation of Ni into the NiO NWs, which is sustained by the carrying gas. During this process, the electric field of more than 10<sup>6</sup> V cm<sup>-1</sup> developed between Ni and NiO,<sup>33</sup> along with the giant mechanical stress at the interface,<sup>34</sup> may assist the self-organized formation of the NiO NW arrays. It has been reported that in the oxidation of highly textured Ni tapes the crystallographic orientation of the NiO grains is closely correlated with that of the Ni grains underneath.<sup>35</sup> Therefore, the annealing process prior to the NW growth helps to produce highly textured Ni foils and warrants the crystalline alignment of the produced NiO NW arrays. Furthermore, the NiO scale with fine channels limits the reaction rate and helps to protect the Ni foil from being etched excessively. If the oxidation proceeds too fast, the growth



Figure 3. Schematic of the metal-etching-oxidation (MEO) mechanism proposed for the growth of NiO NW arrays. (e) Cross-sectional SEM image of the NiO NW arrays prepared by focused ion beam (FIB) milling. 205

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Figure 4. (a) SEM image of Co-doped NiO NW arrays obtained by using  $CoCl_2$  as the source powder. (b) The normalized (200) peak in XRD pattern of the NiO and Co-doped NiO NW arrays. (c) HRTEM image showing the growth direction along [200]. (d) EDS mappings of Ni and Co across an individual NW.

stress may cause the oxide to separate from the metal due to the insufficient oxide plasticity.<sup>36</sup> This is analogous to the recently reported spontaneous growth of NiSi<sub>x</sub> NWs where polygrained NiO<sub>x</sub> overlayers act as a diffusion barrier to kinetically and spatially control the Ni diffusion during the chemical vapor growth.<sup>37,38</sup> It was shown that the presence of the oxide overlayers on Ni seed layers promote the reproducible one-dimensional growth of NiSi<sub>x</sub> single crystals. Similarly, oxide overlayers play critical roles in our experiments to control the vapor supersaturation and to give the reliable NiO NW growth.

We suggest to term this approach of producing aligned NiO NW arrays the "metal-etching-oxidation"



Figure 5. Effect of the growth temperature on the morphology of NiO NW arrays. Typical SEM images taken on samples grown at substrate temperatures of (a) 900, (b) 940, and (c) 980 °C. (d) Dependence of the NW diameter on the growth temperature.

(MEO) process which captures the essence of the forma- 237 tion mechanism. Furthermore, to achieve direct evi-238 dence to confirm the above scenario, we looked at the 239 cross-sectional SEM image of the NW arrays exposed by 240 using focused ion beam (FIB) milling. As shown in Fig-241 ure 3e, the NiO NWs are imbedded between the NiO 242 scale layer and the Ni foil. Even though significant 243 breaking, melting, and fusing of the NiO NWs occurred 244 because of the large ion milling current, the observed 245 particular columnar structure of the NiO NW arrays sup-246 ports the proposed growth mechanism. However, we 247 should be cautious regarding to the details of the ex-248 act growth mechanism owing to the lack of direct ex-249 perimental evidence and real-time observation. We 250 noted that anisotropic silicon NW arrays have been re-251 cently fabricated via a metal-assisted chemical etching 252 method.<sup>39,40</sup> Although both the reported method and 253 ours rely on anisotropic etching, our approach does not 254 involve the use of any catalyst and appears to be more 255 suitable to prepare NWs of metal oxides. 256

Since etching and oxidation are the two key ele-<br/>ments in the MEO process, chlorides other than NiCl2<br/>should also be capable to initiate the growth. To test<br/>this hypothesis, we chose CoCl2 as the source powder<br/>in the synthesis. At high temperatures, Cl2 gas is pro-<br/>duced as the following:257<br/>258

$$CoCl_2(g) + 1 / 2O_2(g) \rightarrow CoO(s) + Cl_2(g)$$
 (4)

Following a similar growth mechanism as in the NiCl<sub>2</sub> 263 case, NW arrays were obtained. As shown in Figure 4a, 264 the NW arrays are uniform, being 2  $\mu$ m in length and 265 about 100 nm in diameter. In addition, this change of 266 source allows us to introduce Co as a doping element 267 into the NiO NWs. The Co doping process occurs simul-268 taneously with the etching and oxidation process, and 269 the high synthesis temperature assists the efficient dif-270 fusion of Co in the NiO matrix. As shown in the XRD pat- 271 terns in Figure 4b, the (200) peak of the Co-doped NiO 272 NWs shifts toward a lower angle compared with that of 273 the undoped counterpart, which is consistent with the 274 fact that the radius of Co ions (0.0838 nm) is slightly 275 larger than that of the Ni ions (0.0830 nm). The HRTEM 276 image in Figure 4c shows that the single crystal NWs 277 grow along the [200] direction, consistent with the re-278 sults of the NiO NWs. The EDS data suggest a Co dop-279 ing level of ca. 1%. In addition, in the EDS line scans 280 across an individual Co-doped NiO NW (Figure 4d), the 281 Co profile appears to follow the Ni profile very well, in-282 dicating a uniform distribution of the Co element.<sup>41</sup> 283

We further demonstrate that one is able to tune the284morphology of the NiO NWs through adjusting the285growth temperature and the oxygen content in the car-286rying gas. As shown in the SEM images in Figure 5a-c,287the diameter of the NiO NWs increased from 100 to288500 nm as the growth temperature changed from 900289to 980 °C. This clear trend shown in Figure 5d could be290

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291 due to two reasons. One is that a higher growth temperature always results into a NiO scale with larger 292 grains.<sup>42</sup> Since the NW morphology is mainly defined 293 by the Cl<sub>2</sub> gas etching through the grain boundaries, 294 295 larger grains eventually lead to thicker wires. The other is that a higher temperature significantly promotes the 296 Ni oxidation, thus circumvents the etching, which may 297 also result in NWs with larger diameters. At 980 °C, the 298 cross section of the NiO NWs appears to be square-like, 299 300 indicating their single crystal nature.

We found that the growth temperature has little ef-301 fect on the length of the NiO NWs. Instead, the NW length 302 can be well controlled by adjusting the gas content. As 303 shown in the SEM images in Figure 6a-d, shorter NWs F6 304 305 could be obtained if a carrying gas with lower oxygen content was used. The length and diameter of NWs were 306 measured for these samples, and the statistical results are 307 shown in Figure 6e and f. The NW length increased from 308 1 to 10  $\mu$ m with the increasing oxygen content from 0.5% 309 310 to 15%, while the diameter changed only slightly. This effective length control originates from the fact that a 311 higher oxygen concentration promotes the oxidation 312 and protects the NW core from the excessive etching. 313 Consequently, the Cl<sub>2</sub> etching gas goes deeper into the 314 Ni foil, forming longer NiO NWs. Since the diameter and 315 the length of the NiO NWs can be independently con-316 317 trolled by the growth temperature and the carrying gas content, the synthesis route herein gives lots of flexibility 318 in the morphology control. 319

Recently NiO thin films have been reported for their 320 potential applications in the next generation resistive 321 322 RAM (ReRAM) devices, which may serve as alternatives to the current nonvolatile flash memory technology.43,44 323 Although the switching model involving the formation 324 and rupture of conducting filaments is widely used to ex-325 plain the experimental observations, the complex switch-326 ing mechanisms in NiO warrants further investigations. 327 Very recently, reversible resistive switching behaviors 328 have been demonstrated in NiO nanowires fabricated in 329 anodized aluminum oxide membranes<sup>13</sup> and MgO/NiO 330 core/shell heterostructured NWs.<sup>45</sup> Our preliminary results 331 suggest that the NiO NW arrays grown by the MEO 332 method also show bipolar resistive switching (Figure 7). F7 333 We scratched near the edge of the sample to reach the 334 Ni foil underneath the NWs, and then the exposed Ni foil 335 and a Pt pad deposited on the NiO NW arrays served as 336 the electrodes for the switching experiments (the inset of 337 338 Figure 7). When a voltage was applied as  $0 \rightarrow 4$  V, the current through the Pt/NiO/Ni device increased dramatically 339 to the  $\mu$ A range, indicating a "SET" process. The device 340 can be switched back to the initial high resistance state 341 by applying a voltage sweep as  $0 \rightarrow -4$  V, indicating a 342 343 "RESET" process. The ON/OFF ratio between the high resistance state and the low resistance state reached 2 or-344 ders of magnitude. 345

346 Furthermore, the novel synthesis approach pre-

347 sented here can also be applied to other metal oxides.



Figure 6. Morphology evolution of the NiO NW arrays with different growth atmospheres: (a)  $0.5\% O_2$ , (b)  $5\% O_2$ , (c)  $10\% O_2$ , and (d)  $15\% O_2$  in the carrying gas. (e) Dependence of the NW length on the oxygen content. (f) Dependence of the NW diameter on the oxygen content.

One prerequisite of the application of this method is the formation of a thin granular oxide scale covering the metal foil which critically facilitates the etching process. Considering that the Gibbs energy of forming CoO is similar to that of forming NiO,<sup>46</sup> we tried our MEO method on the fabrication of CoO NW arrays. Indeed we found that CoO NW arrays can also be grown on Co foils following a similar route, as shown in Figure 8a. Our preliminary results suggest that, similar to NiO, NWs of CoO can also be grown *via* the MEO method. In this case, we used Co foils as the substrate and CoCl<sub>2</sub> as the source. The experimental growth conditions are similar to those for the growth of NiO NWs. As shown in the SEM picture, the CoO NW quality is yet to be opti-



Figure 7. I-V characteristics of the NiO NW arrays. Inset shows the schematic diagram of the measurement.

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Figure 8. Top-view SEM image and XRD data of cobalt oxide (CoO) NW arrays

> mized; the NWs appear shorter than the NiO counterpart and the NWs diameters are not uniform. Nevertheless, the XRD data in Figure 8b suggests that the growth product is CoO without second phase. Thus these preliminary results encourage the application of this MEO method to the synthesis of other metal oxide nanowires.

#### **EXPERIMENTAL SECTION**

Nanowire Synthesis. The synthesis of the NiO NW arrays was carried out in a home-built vapor transport system comprising a horizontal tube furnace (Lindberg/Blue mini-mite) and a gas delivery and pumping system.<sup>28-30</sup> NiCl<sub>2</sub> power with a weight of 0.1 g (Aldrich, 98%) was introduced into two one-end-open quartz tubes and put opposite to each other in the middle of the furnace quartz tube. Ni foils (0.125 mm thick, Aldrich 99.9%) were cut into small pieces with a typical size of 10 mm imes 10 mm and cleaned by acetone. After cleaning, the foils were mechanically polished using a Buehler MiniMet 1000 polisher, following three step: (1) polishing with SiC paper disks (120-grit) under water cooling; (2) using rigid grinding disks (Metadi Supreme, 3-µm PC); (3) using microcloth pad with 0.05-µm alumina suspension. Subsequently, the foils were electrochemically polished in a mixture of HClO<sub>4</sub> and C<sub>2</sub>H<sub>6</sub>O (1:4 volume ratio). As a final step of foil preparation, the Ni foils were annealed at 1000 °C for 8 h in a gas mixture of 90% Ar and 10% H<sub>2</sub> in order to decrease the internal stress and to further improve the crystalline quality. After these polishing and annealing procedures, the Ni foils were placed at the middle of the furnace tube between the small tubes containing the NiCl<sub>2</sub> powder. For the growth, the quartz tube was evacuated to a background vacuum of a few mbar, and the furnace was heated up to 600 °C at a rate of 50 °C/min. Then, a mixture gas of Ar and O2 was introduced with a constant flow rate of 100 sccm, and the pressure inside the guartz tube was maintained at 800 mbar. Finally, the furnace was heated up further to the growth temperature and maintained for 15 min. After the furnace was cooled to room temperature, a layer of green products was grown on the surface of the Ni foils.

Characterization. A JEOL JSM-6700F field emission scanning electron microscope (SEM) and a JEOL 2100 high resolution transmission electron microscope (HRTEM) were used to study the morphology and structure of the samples. The composition was determined by an attached energy-dispersive X-ray spectrometer (EDS). The X-ray diffraction (XRD) analysis was carried out using a Bruker AXS D8 Advanced powder diffractometer with Cu K $\alpha$  radiation. Focused ion beam (FIB) milling was performed using a XT Nova Nanolab 200. The electrical characterizations were carried out at room temperature on a probe station equipped with a Keithley 4200 semiconductor parameter analyzer.

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#### CONCLUSIONS

Single crystal NiO NW arrays have been synthesized 370 for the first time through a facile vapor-based metal-371 etching-oxidation method. The diameter and the 372 length of the nanowire can be well controlled by adjust- 373 ing the growth temperature and the carrying gas con-374 tent. Furthermore, by replacing NiCl<sub>2</sub> with CoCl<sub>2</sub> in the 375 source powder, uniform Co doping can be introduced 376 in the NiO NWs. We also used CoO as an example to 377 demonstrate that this method can be applied to syn-378 thesize NWs of other oxides. In the general context, it 379 is well-known that materials belonging to the high-380 symmetry cubic space groups are notoriously difficult 381 to grow into anisotropic single crystalline nanowires. 382 Therefore, our method presents a novel and general 383 route to synthesize low dimensional metal oxide nano-384 structures, and will help to advance the research on 385 their functionalities and applications. 386

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Supporting Information Available: The change of Ni foil crys-433 tal quality after annealing; SEM image of the NiO NW arrays 434 milled by focused ion beam; the TEM images of the nanowire 435 with [220] growth direction; the weight change and the XRD pat-436 terns of the Ni foil taken at various growth stages used for fur-437 ther growth mechanism discussion. This material is available free 438 of charge via the Internet at http://pubs.acs.org. 439

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